# Pre-Report 2DA1201Y PNP TRANSISTOR

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### **Abstract**

Analysis and extraction of model parameters and performance characterization of 2DA1201Y PNP transistor.

# 1 Theoretical Expressions

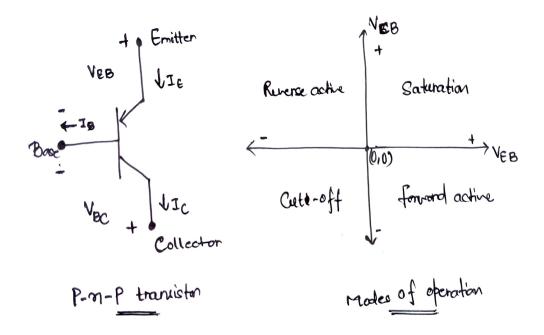


Figure 1: Structure of PNP BJT

For the P-N-P transistor, as shown in Figure 2, we have:

- $N_{AE}$  = Doping concentration of acceptor atoms in the emitter region.
- $N_{DB}$  = Doping concentration of donor atoms in the base region.
- $N_{AC}$  = Doping concentration of acceptor atoms in the collector region.

In the forward active mode of operation of the P-N-P BJT, when  $V_{EB} > 0$  and  $V_{CB} < 0$ , we will have the injection of electrons into the emitter from the base and holes into the base from the emitter. The electron concentration at the emitter-base depletion layer surface is given by:

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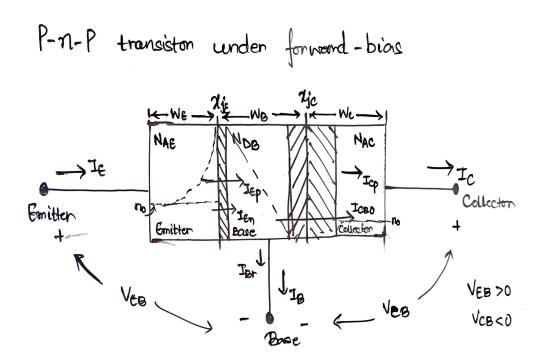


Figure 2: Working of PNP BJT in forward active mode

 n<sub>p</sub> = Concentration of Electrons injected from the base into the emitter at the depletion layer surface.

$$n_p = n_{po} \exp\left(\frac{V_{EB}}{V_t}\right); n_{po} = \frac{n_i^2}{N_{AE}} \tag{1}$$

where  $V_t$  is the thermal voltage &  $n_i$  is the intrinsic concentration of Carrier at given temperature for all expression. Therefore, Excess Electron concentration at Depletion layer surface after injection on emitter side is given by,

$$\Delta n_p = n_p - n_{po} = n_{po} \left[ \exp\left(\frac{V_{EB}}{V_t}\right) - 1 \right]$$
 (2)

 p<sub>n</sub> = Concentration of Holes injected from the emitter into the base at the depletion layer surface.

$$p_n = p_{no} \exp\left(\frac{V_{EB}}{V_t}\right); p_{no} = \frac{n_i^2}{N_{DB}}$$
(3)

Since, The Collector-Base junction is under Reverse bias is under reverse bias, due to carrier extraction at surface the hole concentration at surface on base side is given by,

$$p_{nCB} = p_{no} \exp\left(\frac{V_{CB}}{V_t}\right); V_{CB} < 0 \Rightarrow p_{nCB} \approx 0$$
 (4)

The base width  $(W_E)$  of the transistor is kept much smaller than the diffusion length  $(L_p)$  of the holes, So that all the holes injected from emitter side travels through the base region with minimum injection resulting in a Collector current much greater than reverse saturation current of Base-Collector such that,  $I_C \approx I_E$ .

We can define 5 main components of current in BJT as shown in figure 2.

- $I_{Ep}$  = Current due to hole injection on Base side from Emitter.
- $I_{En}$  = Current due to Electron injection on Emitter side from Base.
- $I_{Br}$  = Current due to recombination of holes in base region.
- $I_{Cp}$  = Current due to Collection of holes from base region.
- $I_{CBO}$  = Reverse saturation current across Base-Collector.

# 2 Current Components and Device Parameters

#### **2.1** Emitter Current $(I_E)$

The total emitter current is composed of two components: the hole current injected from the emitter into the base  $(I_{Ep})$  and the electron current injected from the base into the emitter  $(I_{En})$ . Thus, the emitter current is:

$$I_E = I_{Ep} + I_{En} \tag{5}$$

The diffusion current is given by Fick's first law of diffusion:

$$J_p(x) = -qD_p \frac{dp_n(x)}{dx} \tag{6}$$

where  $J_p(x)$  is the hole current density at a distance x into the base,  $D_p$  is the diffusion coefficient of holes, and  $p_n(x)$  is the hole concentration at distance x from the depletion surface. for cross-sectional area A,

$$I_{Ep} = J_p(0)A = qAD_p \left. \frac{dp_n(x)}{dx} \right|_{x=0} \tag{7}$$

From current-continuity equation in steady-state conditions,

$$\frac{d^2 \Delta p_n(x)}{dx^2} = \frac{\Delta p_n(x)}{L_p^2} \tag{8}$$

where  $L_p$  is the diffusion length of holes in the base. The solution to this differential equation for a uniform base width  $W_B$  and boundary conditions at the base-emitter and base-collector junctions is:

$$\Delta p_n(x) = \Delta p_{no} \exp\left(\frac{-x}{L_p}\right); \Delta p_{no} = \frac{n_i^2}{N_{DB}} \left[\exp\left(\frac{V_{EB}}{V_t}\right) - 1\right]$$
 (9)

$$\Delta p_n(0) = \Delta p_{no} = \frac{n_i^2}{N_{DB}} \left[ \exp\left(\frac{V_{EB}}{V_t}\right) - 1 \right]$$
 (10)

Simplification for  $W_B \ll L_p$  from Taylor's expansion,

$$\Delta p_n(x) = \Delta p_{no} \left[1 - \frac{x}{W_B}\right] \tag{11}$$

$$\Rightarrow I_{Ep} = qAD_p \frac{\Delta p_n(0)}{W_B} = \frac{qAD_p n_i^2}{N_{DB} W_B} \left[ \exp\left(\frac{V_{EB}}{V_t}\right) - 1 \right]$$
 (12)

$$I_{Ep} \approx \frac{qAD_p n_i^2}{N_{DB}W_B} \exp\left(\frac{V_{EB}}{V_t}\right)$$
 (13)

Similarly  $I_{En}$  can be found as,

1. For short length Emitter i.e Emitter thickness  $W_E$  « electron diffusion length on emitter side  $L_n$ ,

$$I_{En} \approx \frac{qAD_n n_i^2}{N_{AE} W_E} \exp\left(\frac{V_{EB}}{V_t}\right) \tag{14}$$

## 2. for Long length Emitter

$$I_{En} \approx \frac{qAD_n n_i^2}{N_{AE}L_n} \exp\left(\frac{V_{EB}}{V_t}\right)$$
 (15)

Final Expression for Emitter Current,  $I_E = I_{Ep} + I_{En}$ 

$$I_E = \frac{qAD_n{n_i}^2}{N_{AE}W_E} \exp\left(\frac{V_{EB}}{V_t}\right) + \frac{qAD_p{n_i}^2}{N_{AE}L_n} \exp\left(\frac{V_{EB}}{V_t}\right)$$

Since  $N_{AE} >> N_{DB} \Rightarrow I_E \approx I_{Ep}$  hence,

$$I_E \approx I_{Ep} \approx \frac{qAD_p n_i^2}{N_{DB} W_B} \exp\left(\frac{V_{EB}}{V_t}\right)$$
(16)

# **2.2** Base Current $(I_B)$

The base current is the sum of the current due to recombination of holes in the base region  $(I_{Br})$  and the electron current injected into the emitter from the base minus the collector current:

$$I_B = I_{Br} + I_{En} - I_{CBO} (17)$$

Base current can be found from the charge control model:

$$I_B = \frac{Q_p}{\tau_p} = \frac{qAW_B p_n}{2\tau_p} = \frac{qAW_B p_{n0}}{2\tau_p} \exp\left(\frac{V_{EB}}{V_T}\right)$$

$$I_B = \frac{qAW_B n_i^2}{2N_{DB}\tau_p} \exp\left(\frac{V_{EB}}{V_T}\right)$$
(18)

#### **2.3** Collector Current $(I_C)$

The collector current is due to the collection of holes injected into the base and reverse saturation current which is very small.

$$I_C = I_{cp} + I_{CBO}$$

$$I_C \approx I_{cp} \tag{19}$$

#### **2.4** Base Transport Factor (B)

The base transport factor  $\alpha_T$  is defined as the fraction of holes injected into the base that reach the collector without recombining.

$$B = \frac{I_{Cp}}{I_{Ep}} = \frac{I_{Ep} - I_B}{I_{Ep}} = 1 - \frac{I_B}{I_{Ep}}$$

$$B = 1 - \frac{W_B^2}{2L_p^2}, (L_p^2 = D_P \tau_p)$$
(20)

where  $W_B$  is the base width and  $L_p$  is the diffusion length of holes in the base.

#### **2.5** Emitter Efficiency $(\gamma)$

The emitter efficiency  $\gamma$  is defined as the ratio of the hole current injected into the base to the total emitter current:

$$\gamma = \frac{I_{Ep}}{I_E} = \frac{I_{Ep}}{I_{Ep} + I_{En}} = \left[1 + \frac{I_{En}}{I_{Ep}}\right]^{-1}$$

$$\gamma = \left[1 + \frac{D_n W_B N_{DB}}{D_P L_p N_{AE}}\right]^{-1} \text{(long emitter)}$$

$$\gamma = \left[1 + \frac{D_n W_B N_{DB}}{D_P W_E N_{AE}}\right]^{-1} \text{(short emitter)}$$
(21)

#### **2.6** Current Gain ( $\alpha_f$ and $\beta$ )

The current gain  $\alpha_f$  is the ratio of the collector current to the emitter current:

$$\alpha_f = \frac{I_C}{I_E} \approx \frac{I_{Cp}}{I_{Ep} + I_{En}} = B\gamma \tag{23}$$

The common-emitter current gain  $\beta_f$  is the ratio of the collector current to the base current:

$$\beta_f = \frac{I_C}{I_B} = \frac{I_C}{I_E - I_C} = \frac{\alpha_f}{1 - \alpha_f} \tag{24}$$

## 2.7 Switching Characteristics

$$\tau_f = \frac{W_B^2}{2D_p} \tag{25}$$

# 3 Information extraction from plots

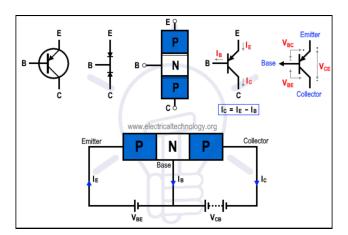


Figure 3: Construction and working of PNP BJT

#### Power limit variation with temperature

- The relation with  $P_t ot$
- Inversion: Images are inverted so that the background black matches with extra black pixels introduced around the corners due to rotation.
- **Erosion**: This is used to reduce the thickness of lines present in the image. As a result, the obstructing lines are almost removed. The thickness of letters also got reduced but they are still good enough to be further used.
- Rotation: 7 copies of each reference character are made with rotation angles of -30, -20, -10, 0, 10, 20, 30 degrees and stored as new reference images in an array. These are used for comparison on the training/testing images.

## Step 2: Cropping and Comparison with Reference Set

- **Cropping**: Obtained test image is cropped using a manually tuned parameter in order to extract last character.
- Dimensionality of images are made consistent through appropriate cropping of reference images.
- Each image is then compared with each of 16 × 7 reference images through the process of 'Subtraction'.

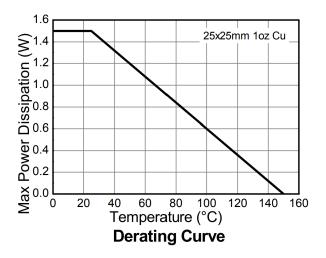


Figure 4: Derating curve

# Step 3: Correct classification based on Subtraction matrix

- Each test image is compared with 16 × 7 reference images and sum of elements of difference matrix(D) is stored in a new matrix.
- Least element of the new matrix gives us the most resembled character and the algorithm outputs the same.

# Step 4: Parity detection

After successful identification of last character, parity of the last character is found by using the modulo operator which gives us the parity of the hexadecimal number itself.

# 4 Hyper-Parameter Tuning

"Selecting an optimal value for a hyper-parameter is often considered an art rather than a science."

Hence, there exists no fixed algorithm to find out the best hyper-parameters. Instead, it depends on its utility in the Machine Learning model .

The hyper-parameters used in our attempt are as follows:

- 1. Monochrome Threshold
- 2. Eroding Thickness
- 3. Cropping Last Character
- 4. Horizontal Cropping of Reference Images
- 5. Vertical Cropping of Reference Images
- 6. Resizing Parameter

#### 4.1 MonochromeThreshold

Firstly, the images are converted to gray-scale to remove the unnecessary information of colors. Then, the images are converted to monochrome using a thresholding parameter, which is determined using the *Otsu's Method*.

#### 4.2 Eroding Thickness

The erosion parameter is the kernel size. Kernel is the structuring element that determines the precise effect of the erosion on the input image. A too low size would not affect at all while a too large kernel size erodes the boundaries of the characters too. A kernel size of 2 gave optimum results as to eroding obstructing lines as well as maintaining legible thickness of characters in image.

#### 4.3 Cropping Last Character

For obtaining the last character which is crucial to parity generation, we crop the test image with a boundary of  $10:100\times360:450$  pixels. This was found manually. We used matplotlib.pyplot to display the image in an XY plot. We found the right X and Y axes limits which bounded a straight image closely, 378:432 and 18:92 respectively(refer Fig.1). Then, cropped it with an offset of 18 horizontally on both sides and an offset of 8 vertically above and below so that the boundary could hold the character even if it was rotated to  $\pm30$  degrees (refer Fig.2). This results in a  $90\times90$  image, with boundaries  $10:100\times360:450$  pixels.



Figure 5: Boundary chosen to Enclose  $\pm 30^{\circ}$  Rotated ones

#### 4.4 Horizontal Cropping of Reference Images

First limitation is that the reference image should also be  $90 \times 90$  for subtraction. We cropped the image instead of resizing it from  $100 \times 100$  to  $90 \times 90$ , so that the resolution of image doesn't change. The possible horizontal cropping limits are from 0:90 to 10:100. We have tuned this as a hyper-parameter and found that 5:95 gave 100% accuracy in parity detection.

#### 4.5 Vertical Cropping of Reference Images

The possible vertical cropping limits are from 0:90 to 10:100. We have tuned this as a hyperparameter and found that 3:93 gave 100% accuracy in parity detection.

## 4.6 Resizing Parameter

We resized both test and reference images to the same values after cropping them both to  $90 \times 90$  matrices. We tried to resize the images initially, to a smaller value say,  $50 \times 50$  pixels, to reduce computing time and found a significant drop in accuracy. So, we tried tuning it as a hyper-parameter.

The below heat maps show the Parity Accuracy w.r.t to the resizing hyper-parameter and different cropping hyper-parameters of the reference images. So, from Fig.3(c),(d),(e), we chose the best horizontal crop as 5:95. From Fig.3(d), we chose the best vertical crop as 3:93 and the resizing limit as  $87 \times 87$  pixels.

### **Hyper-Parameter Tuning**

## 5 Conclusion

Based on the above images and fine-tuning of various hyper-parameters, we have reached the following conclusions:

• Using pictures in gray-scale and turning them into monochrome resulted in better identification and reduced the execution time around 3-4 milliseconds.

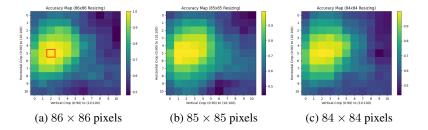


Figure 6: X axis and Y axis represent the vertical crop offset and the horizontal crop offset of the reference images respectively. The red blocks show 100% accuracy in parity detection.

- Optimized sizes of respective images were found through manually looking at the training image and fine-tuning the hyper-parameters for reference images.
- Subtraction method provided an appreciable parity accuracy.

Through the optimization process outlined above, our model achieved a **parity match score of** 1.0 (accuracy of 100%) within an execution time of 7 **milliseconds** per image when 2000 images were used. (subject to change because the first iteration takes around 60 milliseconds due to reference image pre-processing).

## References

- [1] OpenCV Tutorial for Erosion and Image Morphology
- [2] Documentation for Otsu's method
- [3] Algorithm for Subtraction of Image Matrix